

Search Notes

Application/Control No.

09/396,244

Examiner

Cheukfan Lee

Applicant(s)/Patent under
Reexamination

NAGANO, MASATOSHI

Art Unit

2625

SEARCHED

Class	Subclass	Date	Examiner
358	475,509, 487,506	3/22/2006	C.L.
	505		
	463,474		
355	30,40,41		
	67-71		
250	234-236		
382	312		
	318,319		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search: terms include: (IR infrared (infra adj red) invisible (non adj visible)), (dust scratch\$3 (foreign adj matter)	3/22/2006	C.L.
search terms (cont.): contamina\$6), (mode select\$5), skip\$5, (transparen\$5 film\$5 transmissive)		
search terms (cont.): detect\$3 determin\$5 discriminat\$3		
Inventor search		